## Notice of References Cited Application/Control No. 10/017,174 Examiner Binh Q. Nguyen Applicant(s)/Patent Under Reexamination DELL ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,537,403	07-1996	Cloonan et al.	370/352
*	В	US-5,550,815	08-1996	Cloonan et al.	370/396
*	С	US-6,868,084	03-2005	Konda, Venkat	370/395.1
*	D	US-5,555,243	09-1996	Kakuma et al.	370/352
*	E	US-5,124,978	06-1992	Chao, Hung-Hsiang J.	370/422
*	F	US-5,157,654	10-1992	Cisneros, Arturo	370/414
*	G	US-5,361,255	11-1994	Diaz et al.	370/374
*	Н	US-5,440,553	08-1995	Widjaja et al.	370/411
*	1	US-5,631,902	05-1997	Yoshifuji, Yuuki	370/388
*	J	US-5,689,500	11-1997	Chiussi et al.	. 370/235
*	К	US-5,754,120	05-1998	Argentati, Merico Edward	340/2.22
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.